

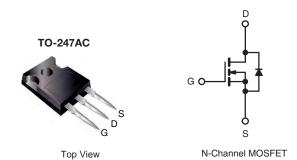
# N-Channel 500-V (D-S) Super Junction MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	500			
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.115		
Q <sub>g</sub> (Max.) (nC)	86			
Q <sub>gs</sub> (nC)	14			
Q <sub>gd</sub> (nC)	25			
Configuration	Single			

### **FEATURES**

- Low figure-of-merit (FOM): Ron x Qg
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)





### **APPLICATONS**

- · Hard switched topologies
- Power factor correction power supplies (PFC)
- Switch mode power supplies (SMPS)
- Computing
  - PC silver box / ATX power supplies
- Lighting
  - Two stage LED lighting

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	500	V	
Gate-Source Voltage			$V_{GS}$	± 30	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C T <sub>C</sub> = 100 °C		30	А	
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	ID	18		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	105		
Linear Derating Factor				0.2	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	273	mJ	
Maximum Power Dissipation			P <sub>D</sub>	280	W	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Drain-Source Voltage Slope	$V_{DS} = 0 V t$	V <sub>DS</sub> = 0 V to 80 % V <sub>DS</sub>		65		
Reverse Diode dV/dt <sup>d</sup>		dV/dt	25	- V/ns		
Soldering Recommendations (Peak Temperature	) c for	for 10 s		300	°C	

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 4.4 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \leq I_{D}, \, dI/dt = 100 \; A/\mu s, \, starting \; T_{J} = 25 \; ^{\circ}C.$

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.5	C/VV	

服务热线:400-655-8788

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PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static					•		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.59	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_D = 250 \mu A$		-	4.0	V
Oala Oa and Ladan	1	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 30 V		-	-	± 1	μΑ
Zero Gate Voltage Drain Current		V <sub>DS</sub> =	$V_{DS} = 500 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	1	μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 400 \			-	25	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 12 A	-	0.115	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 12 A		-	6.6	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ $f = 1 \text{ MHz}$		-	1980	-	pF
Output Capacitance	C <sub>oss</sub>			-	105	-	
Reverse Transfer Capacitance	$C_{rss}$			-	8	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		-	105	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	285	-	
Total Gate Charge	Qg			-	57	86	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$ $I_D = 12 \text{ A}, V_{DS} = 400 \text{ V}$		-	14	-	nC
Gate-Drain Charge	Q <sub>gd</sub>				25	-	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 400 \text{ V}, I_{D} = 12 \text{ A}$ $R_{g} = 9.1 \Omega, V_{GS} = 10 \text{ V}$		-	19	38	ns
Rise Time	t <sub>r</sub>			-	36	72	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	57	86	
Fall Time	t <sub>f</sub>			-	29	58	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	0.56	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	12	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	50	- A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 16.5 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \text{ °C}, I_F = I_S,$ $dI/dt = 100 \text{ A/}\mu\text{s}, V_R = 25 \text{ V}$		-	338	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	5.3	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	29	-	A

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

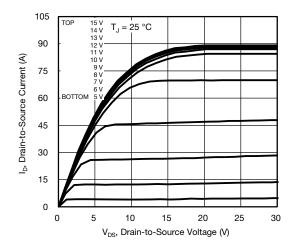


Fig. 1 - Typical Output Characteristics

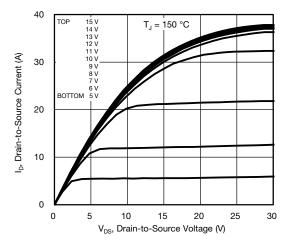


Fig. 2 - Typical Output Characteristics

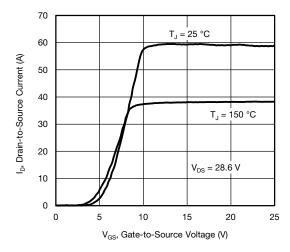


Fig. 3 - Typical Transfer Characteristics

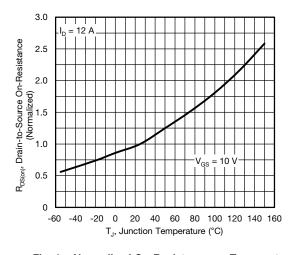


Fig. 4 - Normalized On-Resistance vs. Temperature

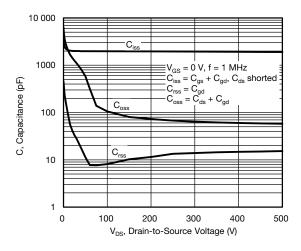


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

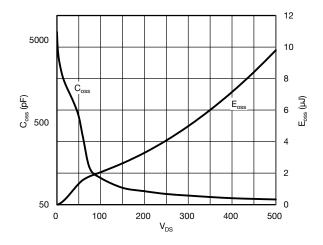


Fig. 6 -  $C_{\mbox{\scriptsize OSS}}$  and  $E_{\mbox{\scriptsize OSS}}$  vs.  $V_{\mbox{\scriptsize DS}}$ 



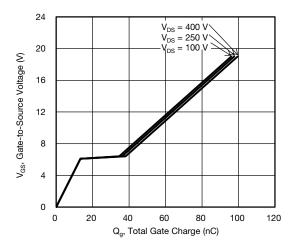


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

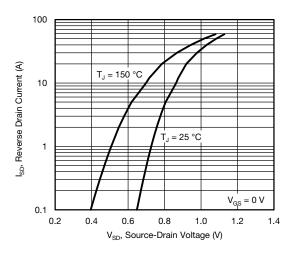


Fig. 8 - Typical Source-Drain Diode Forward Voltage

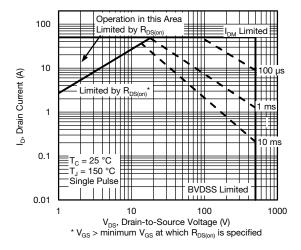


Fig. 9 - Maximum Safe Operating Area

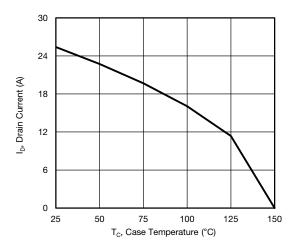


Fig. 10 - Maximum Drain Current vs. Case Temperature

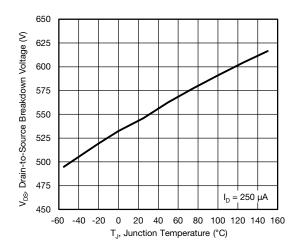


Fig. 11 - Typical Drain-to-Source Voltage vs. Temperature



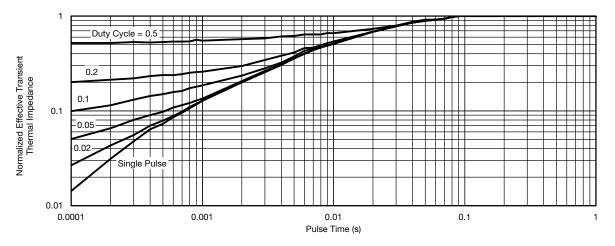


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

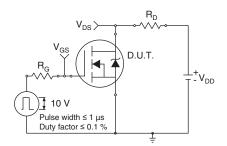


Fig. 13 - Switching Time Test Circuit

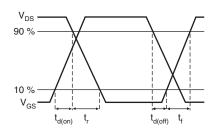


Fig. 14 - Switching Time Waveforms

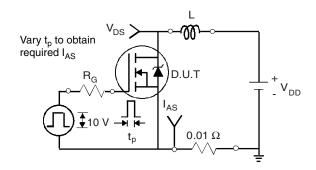


Fig. 15 - Unclamped Inductive Test Circuit

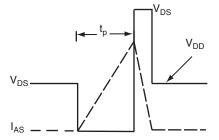


Fig. 16 - Unclamped Inductive Waveforms

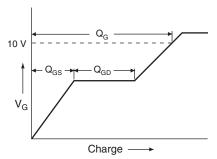


Fig. 17 - Basic Gate Charge Waveform

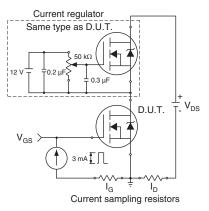
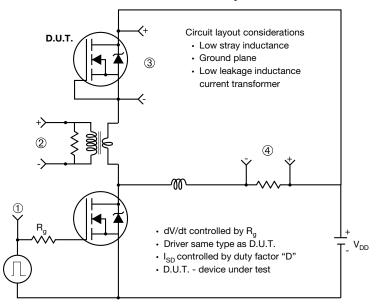


Fig. 18 - Gate Charge Test Circuit



## Peak Diode Recovery dV/dt Test Circuit



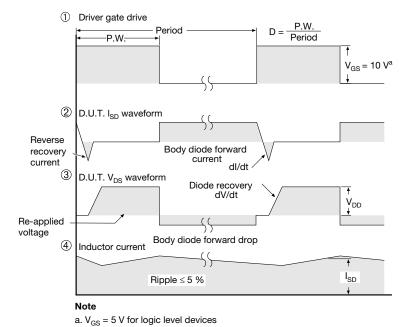


Fig. 19 - For N-Channel



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